

**Search Notes**

Application/Control No.

10/535,171

Examiner

Huyen Le

Applicant(s)/Patent under  
Reexamination

FUKUI ET AL.

Art Unit

3751

**SEARCHED**

Class	Subclass	Date	Examiner
401	99 107-108	10/12/2006	HL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR